

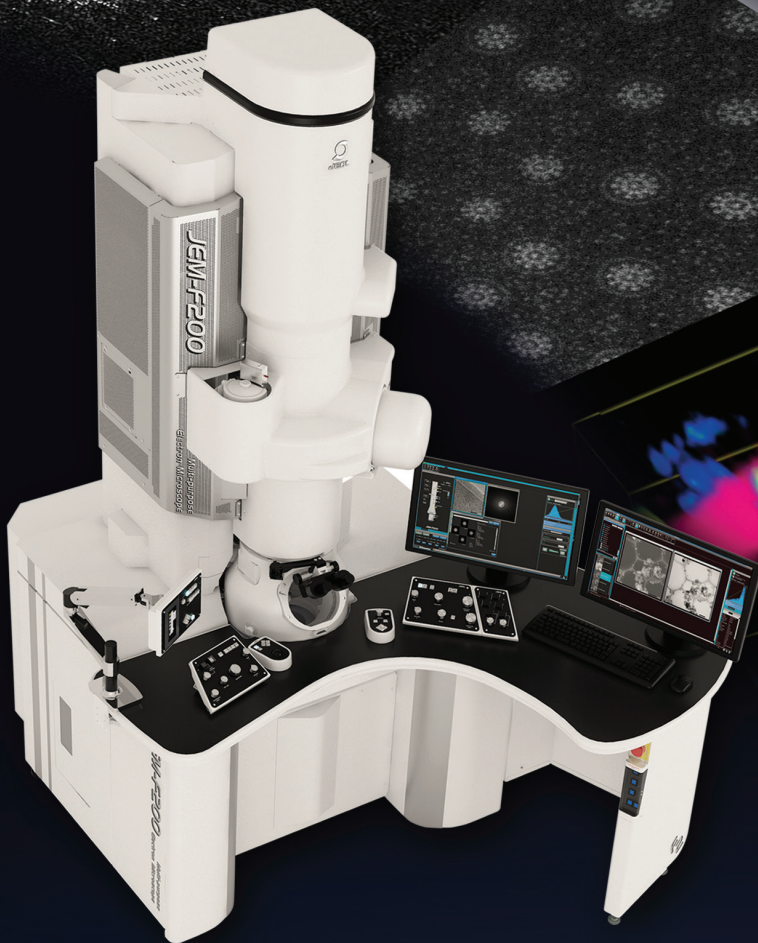
NO COMPROMISE

ATOMIC RESOLUTION + FAST ANALYSIS

The New "Go-To" TEM from JEOL

F2

- Cold FEG boosts probe current
- Fast 3D EDS with dual SDD
- Wide-field STEM-EELS spectrum imaging
- Push-button beam conditions
- Ultra-stable, ultra-fast



10 nm⁻¹

2 nm

JEOL

Solutions for Innovation



www.jeolusa.com
salesinfo@jeol.com • 978-535-5900

Learn more at www.jeolusa.com/F2

*STEM-HAADF image of Quasicrystal • Courtesy of Professor Emeritus K. Hiraga - Tohoku University

H																			He
Li	Be											B	C	N	O	F		Ne	
Na	Mg											Al	Si	P	S	Cl		Ar	
K	Ca	Sc	Ti	V	Cr	Mn	Fe	Co	Ni	Cu	Zn	Ga	Ge	As	Se	Br		Kr	
Rb	Sr	Y	Zr	Nb	Mo	Tc	Ru	Rh	Pd	Ag	Cd	In	Sn	Sb	Te	I		Xe	
Cs	Ba	La	Hf	Ta	W	Re	Os	Ir	Pt	Au	Hg	Tl	Pb	Bi	Po	At		Rn	
Fr	Ra	Ac	Rf	Db	Sg	Bh	Hs	Mt	Ds	Rg	Cn	Uut	F1	Uup	Lv	Uus		Uuo	

Ce	Pr	Nd	Pm	Sm	Eu	Gd	Tb	Dy	Ho	Er	Tm	Yb	Lu
Th	Pa	U	Np	Pu	Am	Cm	Bk	Cf	Es	Fm	Md	No	Lr

Now Invent.™



THE MATERIALS SCIENCE COMPANY®

catalog: americanelements.com

©2001-2014. American Elements is a U.S. Registered Trademark.